

# **Search Notes**



**Application/Control No.**

10/524,384

**Examiner**

Christopher P. Schwartz

**Applicant(s)/Patent under Reexamination**

BAYER ET AL.

**Art Unit**

3683

## **SEARCHED**

Class	Subclass	Date	Examiner
188	1.11E	12/3/2007	CPS
	1.11L		
	71.9		
	72.7		
	72.8		
	158		
	162		
338	2		

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST ^		